

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/723,037	KLIER, JAN	
Examiner Jinhee J. Lee		Art Unit 2174	Page 1 of 1	

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0169297	09-2003	Lay et al.	345/772
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002149315 A	05-2002	Japan	SEKI et al.	
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	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	English abstract of JP02002149315, Seki et al. May 24, 2002
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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